


Search Notes 	Application/Control No. 10632499	Applicant(s)/Patent Under Reexamination OLSCHEWSKI, FRANK
	Examiner Dennis Rosario	Art Unit 2624

SEARCHED			
Class	Subclass	Date	Examiner
382	103	3/6/08	DR
348	169	3/6/08	DR

SEARCH NOTES		
Search Notes	Date	Examiner
East, all dB	3/6/08	DR
ACM-+microscope +trajectory +vector-	3/6/08	DR
IEEE- (((microscope)<in>metadata)<and>((track*)<in>metadata))<and>((vector) <in>metadata))-	3/6/08	DR

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner